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**AEHR TEST SYSTEMS RECEIVES ANOTHER ORDER FOR ITS
NEW ADVANCED BURN-IN AND TEST SYSTEM (ABTS™)**

Fremont, CA (July 2, 2009) - Aehr Test Systems (Nasdaq: AEHR), a leading supplier of semiconductor test and burn-in equipment, today announced it has received an order for its new Advanced Burn-in and Test System (ABTS) from a leading US aerospace company. The system is configured for burning-in and testing high pin count logic devices.

“This will be our first shipment of a high pin count system. It will be used for reliability testing of complex logic for aerospace and military applications,” said Greg Perkins, vice president of worldwide sales and service at Aehr Test Systems. “The customer’s primary need is the flexibility to provide 32M vectors on all 320 I/Os in the system plus the ability to capture per pin device failures while doing test during burn-in. We have sold the ABTS into a wide range of Test and Burn-in applications in both Asia and Europe.”

The ABTS family of products is based on a new hardware and software architecture that is designed to address not only today’s devices, but also future devices for many years to come. It can test and burn-in memory as well as both high-power logic and low-power logic in addition to high pin count logic. It can be configured to provide individual device temperature control for devices up to 50W or more and with up to 320 I/O channels. It uses N+1 redundancy technology for many key components in the system to provide the highest possible system uptime.

Come see the new ABTS system in Aehr Test Systems booth #430 at Semicon West in San Francisco at the Moscone Center, July 14 to 16.

About Aehr Test Systems

Headquartered in Fremont, California, Aehr Test Systems is a leading worldwide provider of systems for burning-in and testing memory and logic integrated circuits and has an installed base of more than 2,500 systems worldwide. Aehr Test has developed and introduced several innovative products, including the ABTS, FOX™, MTX and MAX systems and the DiePak® carrier. The FOX system is a full wafer contact test and burn-in system. The MTX system is a massively parallel test system designed to reduce the cost of memory testing by performing both test and burn-in on thousands of devices simultaneously. The MAX system can effectively burn-in and functionally test complex

devices, such as digital signal processors, microprocessors, microcontrollers and systems-on-a-chip. The DiePak carrier is a reusable, temporary package that enables IC manufacturers to perform cost-effective final test and burn-in of bare die. For more information, please visit the Company's website at www.aehr.com.

Safe Harbor Statement

This release contains forward-looking statements that involve risks and uncertainties relating to projections regarding customer demand and acceptance of Aehr Test's products. Actual results may vary from projected results. These risks and uncertainties include, without limitation, acceptance by customers of the ABTS technology, acceptance by customers of the ABTS systems shipped upon receipt of a purchase order and the ability of new products to meet customer needs or perform as described. See Aehr Test's recent 10-K, 10-Q and other reports from time to time filed with the Securities and Exchange Commission (SEC) for a more detailed description of the risks facing our business. The Company disclaims any obligation to update information contained in any forward-looking statement to reflect events or circumstances occurring after the date of this press release.

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